



## Release Notes

# WITE32™

Version 2.52  
09/08/2000

### Introduction

The 2.52 release incorporates new features introduced after the WITE32 2.51 release. (This document uses the WITE32 2.51 release notes as a base line for comparison.)

### Modifications

1. Spinstand S-1701A+ support. The S-1701A+ spinstand model is an improved modification of S-1701A model. It is fully supported in WITE32 ver. 2.52. To work with S-1701A+ spinstand, you need to select the spinstand driver named 1701A in the Product Selection dialogue box on WITE32 startup. The same 1701A driver is used for both models S-1701A and S-1701A+.

**NOTE:** It is NOT recommended to run older versions of WITE32 with S-1701A+ spinstand. If you run older version of WITE32 with S-1701A+ spinstand, perform spinstand alignment, and then switch to WITE32 ver. 2.52 and above, your spinstand alignment data will be lost. Should it happen, please redo the alignment in new version of WITE32.

2. The new *TPWrRdWidth* result was added to the Numeric output of the Track Profile test. The *TPWrRdWidth* value is the sum of the measured write width and the read width of the head:

$$TPWrRdWidth = TPWrWidth + TPRdWidth$$

3. The new *3T\_WidthSum* result was added to the Numeric output of the Triple Track test. The *3T\_WidthSum* value is the sum of the measured write width and the read width of the head:

$$3T\_WidthSum = Write\ Width + Read\ Width$$

4. Two new results *WrRdWidth* and *WrRdDelta* were added to the Graphic output of the Track Profile test. The *WrRdWidth* value is the sum of the measured write width and read width of the head, and the *WrRdDelta* is the difference of the measured write width and the read width of the head:

$$WrRdWidth = WrWidth + RdWidth$$

$$WrRdDelta = WrWidth - RdWidth$$

## **Fixed Bugs**

1. An intermittent bug in the Digital Parametric test setup dialogue box. When you create a new zone, immediately go to the new zone, and open the Digital Parametric test setup dialogue box, you may not get the new zone configuration data displayed in the window.
2. Zone/setup and WITE32 external test modules bug. If an external test module is not selected when a new zone is created, no new zone configuration record is created for the tests of this external mode. If you try to open the setup window for the new zone/setup, no data will be displayed. This bug occurred only for the following Guzik test modules: Parametric tests, Composite tests, MR tests, Digital Parametric tests. This bug did not affect custom modules created using WDK32.
1. An overwrite frequency of 360–500 Mflux/s cannot be selected in the Overwrite test for RWA-1601/RWA-1632.
2. The “SNR” result name of the Spectral SNR test conflicts with the “SNR” result name of the regular SNR test. The result name has been changed to "SpectralSNR".
3. The error message “Error: WrCurrTo: value is bigger than expected:” occurs when a VTC5410 head amplifier and M16+ PRML Chip are installed. The Write Current and Read Bias optimization range was decreased by 0.2 mA/mV to fix the problem.
4. The Popcorn noise test fails with certain configuration settings in the Positive sector mode. As a result of the fix, the number of write-to-read transitions per revolution may decrease, which leads to the slight increase of test execution time.

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